

<b>Notice of References Cited</b>	Application/Control No. 10/517,381	Applicant(s)/Patent Under Reexamination KANEKO ET AL.	
	Examiner Tejal J. Gami	Art Unit 2193	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0069795 A1	04-2003	Boyd et al.	705/22
*	B	US-2003/0093229 A1	05-2003	Wang Ho, Chris Meichung	702/27
*	C	US-2005/0197786 A1	09-2005	Kataria et al.	702/019
*	D	US-7,039,606 B2	05-2006	Hoffman et al.	705/26
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 01/65441	09-2001	WO	Desouza, Walter	---
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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